# 1. General description

AC Thyristor Triac power switch in a SOT404 (D2PAK) surface mountable plastic package with self-protective clamping capabilities against low and high energy transients. This "series CTN" triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)}$  = 150 °C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

## 2. Features and benefits

- Clamping structure ensuring safe high over-voltage withstand capability
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- High minimum I<sub>GT</sub> for guaranteed immunity to gate noise
- Full cycle AC conduction
- Over-voltage withstand capability to IEC 61000-4-5
- Pin compatible with standard triacs
- Planar passivated for voltage ruggedness and reliability
- Protective self turn-on capability for high energy transients
- Safe clamping capability for low energy over-voltage transients
- Less sensitive gate for high noise immunity
- Surface mountable package
- Triggering in three quadrants only
- Very high immunity to false turn-on by dV/dt and IEC 61000-4-4 fast transient
- Package meets UL94V0 flammability requirement
- Package is RoHS compliant

# 3. Applications

- AC fan, pump and compressor controls
- Highly inductive, resistive and safety loads
- Large and small appliances (White Goods)
- Reversing induction motor controls
- Applications subject to high temperature (T<sub>i(max)</sub> = 150 °C)

#### 4. Quick reference data

### Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DRM}$	repetitive peak off-		-	-	800	V
	state voltage					





Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 20 \text{ ms}$ ; Fig. 4; Fig. 5	-	-	80	A
Tj	junction temperature		-	-	150	°C
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{mb} \le 131$ °C; Fig. 1; Fig. 2; Fig. 3	-	-	8	Α
$V_{PP}$	peak pulse voltage	T <sub>j</sub> = 25 °C; non-repetitive, off-state; Fig. 6	-	-	2	kV
Static char	acteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; } Fig. 8$	5	-	35	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } \frac{\text{Fig. 8}}{\text{C}}$	5	-	35	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	5	-	35	mA
V <sub>CL</sub>	clamping voltage	$I_{CL}$ = 0.1 mA; $t_p$ = 1 ms; $T_j$ = 25 °C	850	-	-	V
Dynamic c	haracteristics		1			
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	4000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; exponnetial waveform; gate open circuit	2000	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 8 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; gate open circuit; snubberless condition	12	-	-	A/ms

# 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	СМ	common	mb	LD 
2	LD	load		G
3	G	gate		G—   CM
mb	LD	mounting base; load	1 3 D2PAK (SOT404A)	003aaf296

# 6. Ordering information

### Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
ACTT8B-800CTN	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404A			

# 7. Marking

### Table 4. Marking codes

Type number	Marking code
ACTT8B-800CTN	ACTT8B-800CTN

# 8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{mb} \le 131$ °C; Fig. 1; Fig. 2; Fig. 3	-	8	A
I <sub>TSM</sub>	non-repetitive peak on-state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 20 \text{ ms}$ ; Fig. 4; Fig. 5	-	80	A
		full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 16.7 \text{ ms}$	-	88	A
I <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; sine-wave pulse	-	32	A <sup>2</sup> s
dl <sub>T</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 70 mA	-	100	A/µs
I <sub>GM</sub>	peak gate current	t = 20 μs	-	2	Α
P <sub>GM</sub>	peak gate power		-	5	W
P <sub>G(AV)</sub>	average gate power	over any 20 ms period	-	0.5	W
T <sub>stg</sub>	storage temperature		-40	150	°C
T <sub>j</sub>	junction temperature		-	150	°C
$V_{PP}$	peak pulse voltage	T <sub>j</sub> = 25 °C; non-repetitive, off-state; Fig. 6	-	2	kV

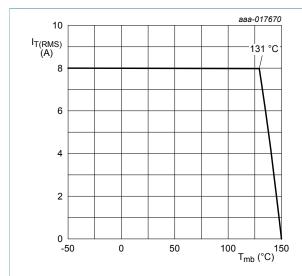
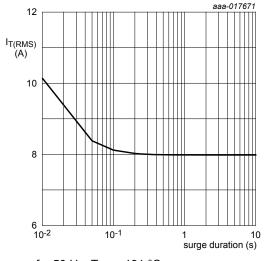


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50 \text{ Hz}; T_{mb} = 131 \,^{\circ}\text{C}$ 

Fig. 2. RMS on-state current as a function of surge duration; maximum values

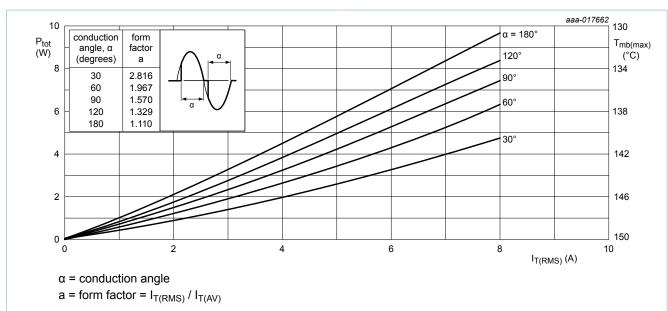


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

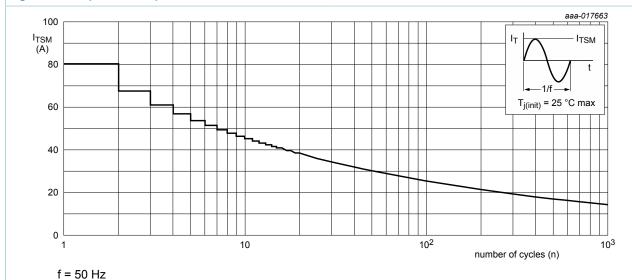


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

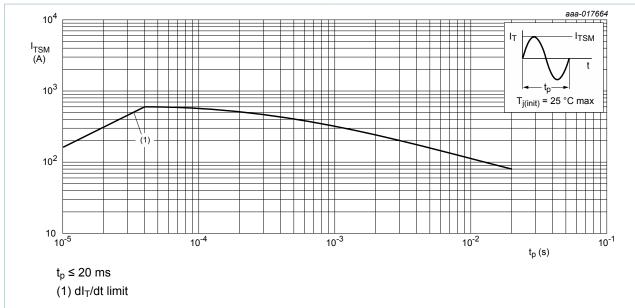


Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

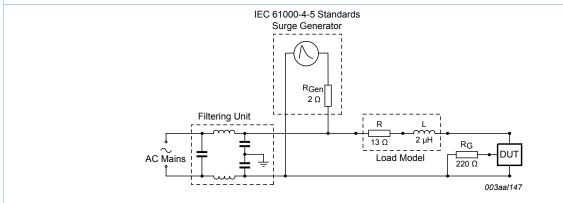


Fig. 6. Test circuit for inductive and resistive loads with conditions equivalent to IEC 61000-4-5

# 9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
from junc	thermal resistance	full cycle; Fig. 7	-	-	2	K/W
	from junction to mounting base	half cycle	-	-	2.4	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air; printed circuit board (FR4) mounted	-	55	-	K/W

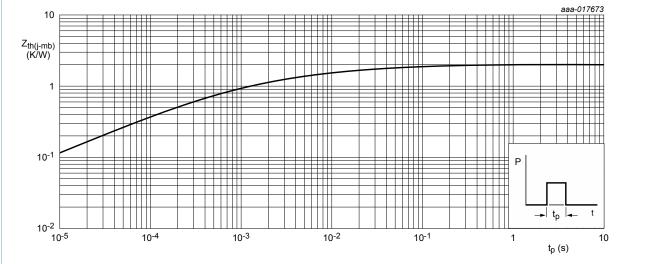
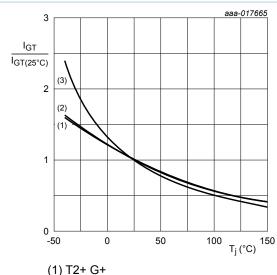


Fig. 7. Transient thermal impedance from junction to mounting base as a function of pulse duration

# 10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; } Fig. 8$	5	-	35	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	5	-	35	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	5	-	35	mA
IL	latching current	$V_D = 12 \text{ V}; I_G = 100 \text{ mA}; LD+ G+;$ $T_j = 25 \text{ °C}; Fig. 9$	-	-	50	mA
		$V_D$ = 12 V; $I_G$ = 100 mA; LD+ G-; $T_j$ = 25 °C; Fig. 9	-	-	60	mA
		$V_D$ = 12 V; $I_G$ = 100 mA; LD- G-; $T_j$ = 25 °C; <u>Fig. 9</u>	-	-	50	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	-	40	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 10 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	-	1.5	V
V <sub>GT</sub>	gate trigger voltage	V <sub>D</sub> = 12 V; I <sub>T</sub> = 100 mA; T <sub>j</sub> = 25 °C; Fig. 12	-	0.8	1	V
		V <sub>D</sub> = 400 V; I <sub>T</sub> = 100 mA; T <sub>j</sub> = 150 °C; Fig. 12	0.2	0.45	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C	-	-	10	μΑ
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	-	2	mA
V <sub>CL</sub>	clamping voltage	$I_{CL}$ = 0.1 mA; $t_p$ = 1 ms; $T_j$ = 25 °C	850	-	-	V
Dynamic c	haracteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	4000	-	-	V/µs
		V <sub>DM</sub> = 536 V; T <sub>j</sub> = 150 °C; exponnetial waveform; gate open circuit	2000	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 8 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; gate open circuit; snubberless condition	12	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 8 \text{ A;}$ $dV_{com}/dt = 10 \text{ V/}\mu\text{s; gate open circuit}$	15	-	-	A/ms
		$V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 8 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit	20	-	-	A/ms



- (2) T2+ G-
- (3) T2- G-

Fig. 8. Normalized gate trigger current as a function of junction temperature

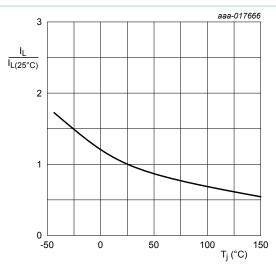


Fig. 9. Normalized latching current as a function of junction temperature

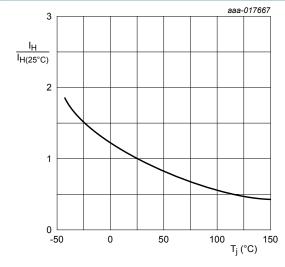
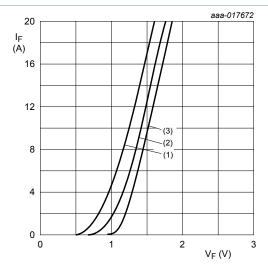
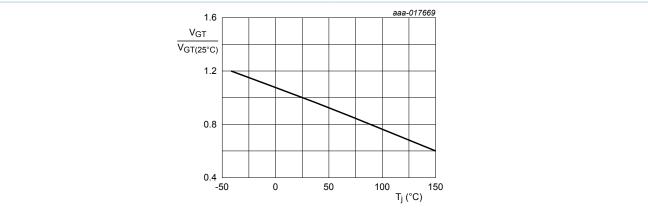


Fig. 10. Normalized holding current as a function of junction temperature

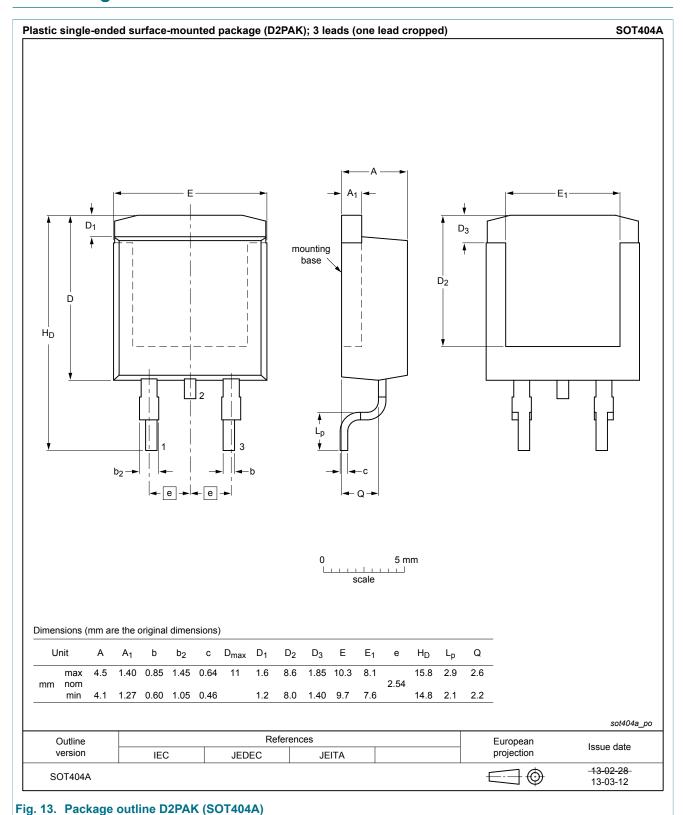


- $V_o$  = 1.089 V;  $R_s$  = 0.028  $\Omega$
- (1) T<sub>j</sub> = 150 °C; typical values
- (2) T<sub>i</sub> = 150 °C; maximum values
- (3) T<sub>i</sub> = 25 °C; maximum values

Fig. 11. On-state current as a function of on-state voltage



# 11. Package outline



# 12. Legal information

#### 12.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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# 13. Contents

1	General description	1
2	Features and benefits	1
3	Applications	1
4	Quick reference data	1
5	Pinning information	2
6	Ordering information	
7	Marking	3
8	Limiting values	4
9	Thermal characteristics	7
10	Characteristics	8
11	Package outline	11
12	Legal information	12
12.1	Data sheet status	12
12.2	Definitions	12
12.3	Disclaimers	12
12.4	Trademarks	13

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